



NIP-261

B
Jfw

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Y. TAKEZAWA et al.

Serial No. 10/082,282 ✓

Group Art Unit 2878

Filed: February 26, 2002

Examiner: D. Monbleau

For: METHOD AND APPARATUS OF
DIAGNOSING DETERIORATION
OF AN ARTICLE

REQUEST FOR INITIALED FORMS PTO-1449

Box: Issue Fee

Commissioner for Patents
Alexandria, Virginia 22314

September 20, 2004

Sir:

Applicants respectfully request the Examiner to initial and return the attached copies of the Forms PTO 1449 (2 pages) filed with an Information Disclosure Statement on February 26, 2002, as an indication that the ten cited documents have been considered. A copy of the date-stamped mailroom receipt as evidence of receipt of the U.S. Patent and Trademark Office is being submitted herewith.

Respectfully submitted,

Daniel J. Stanger
Registration No. 32,846
Attorney for Applicants

MATTINGLY, STANGER & MALUR, P.C.
1800 Diagonal Rd., Suite 370
Alexandria, VA 22314
(703) 684-1120
Date: September 20, 2004

SEP 20 2004

COPY

Sheet 1 of 2

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIP-261	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Y. TAKEZAWA et al	
		FILING DATE February 26, 2002	GROUP

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL	11-330185	11/30/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
AM	2000-131243	05/12/00	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
AN	11-235097	08/27/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
AO	9-222393	08/26/97	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
AP	10-115601	05/06/98	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR	T. Ikeda et al, "Development of the Ultrasonic Degradation Tester for Low Voltage Cables", TRANSACTIONS OF THE INSTITUTE OF ELECTRICAL ENGINEERS OF JAPAN, Vol. 120-B, No. 11, pp. 1437-1442, 2000.
AS	
AT	

EXAMINER	DATE CONSIDERED
----------	-----------------

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



COPY

Sheet 2 of 2

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIP-261	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Y. TAKEZAWA et al	
		FILING DATE February 26, 2002	GROUP

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	11-118773	04/30/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AM	10-19856	01/23/98	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AN	7-35732	02/07/95	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AO	7-245869	09/19/95	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR		
AS		
AT		

EXAMINER	DATE CONSIDERED
----------	-----------------

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.